



<p><b>Searched</b></p> 	<p>Application/Control No.</p> <p>10702036</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>KEKEZ ET AL.</p>
	<p>Examiner</p> <p>Kaplan, Hal I</p>	<p>Art Unit</p> <p>2836</p>

Class	SubClass	Date	Examiner
307.	106	6/1/06	HK

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<b>Search Notes</b>  	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10702036	KEKEZ ET AL.
	Examiner Kaplan, Hal I	Art Unit 2836

Notes	Date	Examiner
EAST (US-PGPUB,USPAT,USOCR,EPO,JPO,DERWENT,IBM_TDB) - See Search History Printout	06/01/2006	HK
EAST (US-PGPUB,USPAT) - See Search History Printout	06/12/2006	HK
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